

Micro-XRD Imaging of Lattice Contraction Induced by Resistive Switching in Chromium-Doped V_2O_3 Mott Insulator

Monday, November 4, 2024 5:00 PM (20 minutes)

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Type of presence

Presence online

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Session Classification: X-ray Microscopy and Spectroscopy of Functional Material

Track Classification: USyNC Workshop